Notice of References Cited

Application/Control No. 10/780,358	Reexamination	Applicant(s)/Patent Under Reexamination CHEN ET AL.		
Examiner	Art Unit			
Mark S. Graham	3711	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,128,963	12-1978	Dano, Pol	264/46.6
	В	US-2003/0104152 A1	06-2003	Sommer, Roland	428/36.91
	С	US-2004/0053716 A1	03-2004	Wu, Нарру	473/564
	D	US-6,626,775	09-2003	Tiitola, Antti-Jussi	473/563
	E	US-4,124,670	11-1978	Cecka et al.	264/45.3
	F	US-2,379,006	06-1945	JOHNSON THEODORE L	. 473/568
	G	US-6,062,996	05-2000	Quigley et al.	473/563
	Н	US-5,407,195	04-1995	Tiitola et al.	473/563
	-	US-5,217,221	06-1993	Baum, Charles S.	473/561
	J	US-2001/0041633 A1	11-2001	Tiitola, Antti-Jussi	473/560
	Κ	US-2003/0104883 A1	06-2003	Caron, Daniel	473/560
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03/097181 A1	11-2004	PCT	McGrath et al.	
	0					
	Р				-	
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	W						
	X						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.